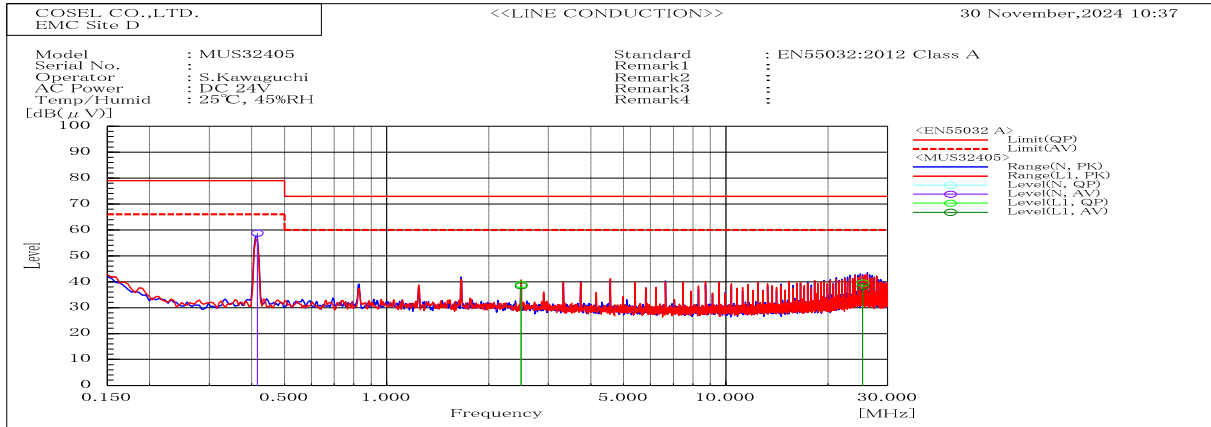
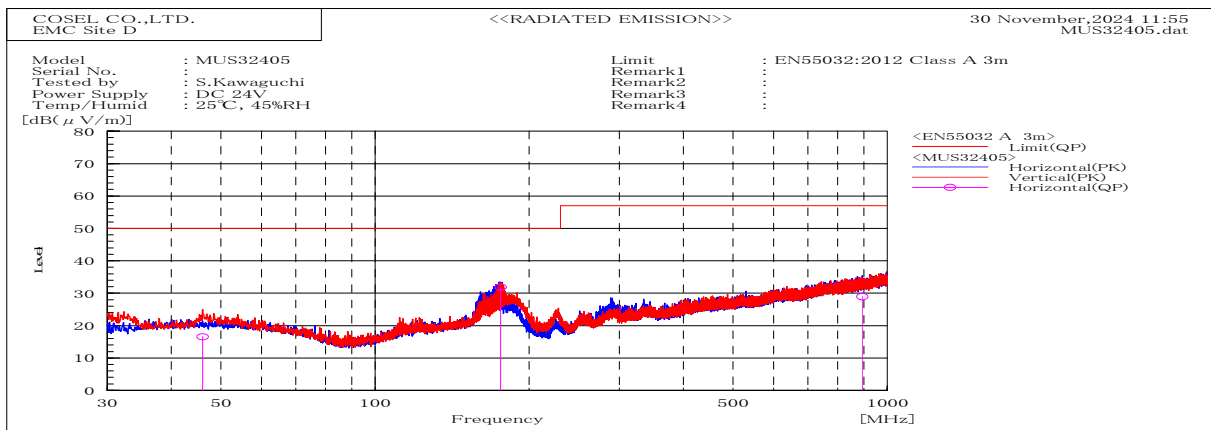


DATA SHEET		Date	30-Nov-24
Model	MUS32405	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



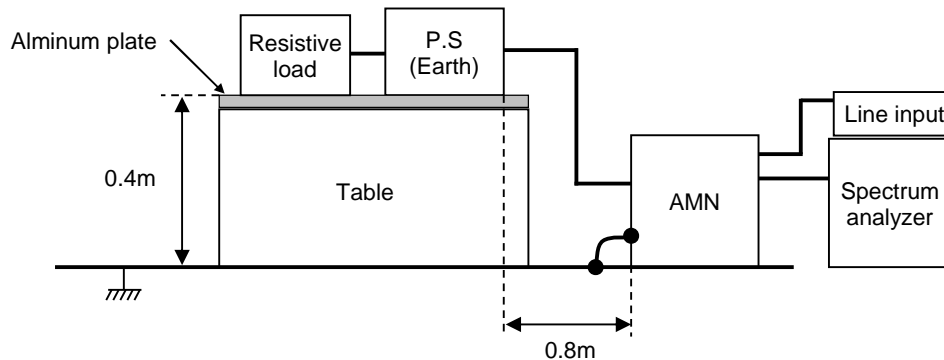
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
2.492	L1	39	38.4	73	60	34	21.6	Pass	
25.342	L1	39.5	38.2	73	60	33.5	21.8	Pass	
0.415	N	58.9	58.8	79	66	20.1	7.2	Pass	



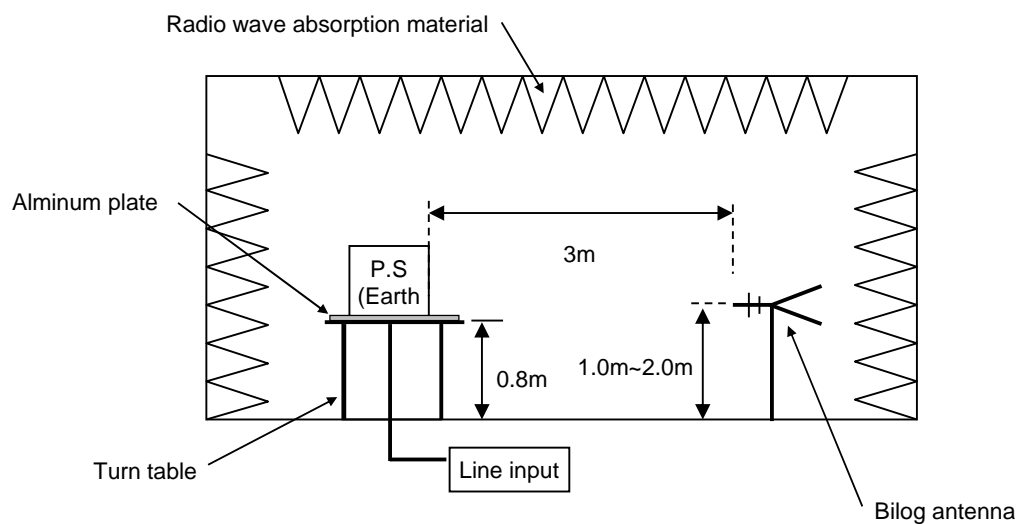
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB(μV/m)	dB(μV/m)	dB				
			QP	QP	QP		cm	deg	
175.768	H	Stable	31.9	50	18.1	Pass	196.2	243.8	
893.623	H	Stable	28.9	57	28.1	Pass	109.9	82.3	
46.079	H	Stable	16.6	50	33.4	Pass	159.5	213.7	

DATA SHEET		Date	30-Nov-24
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

### 1. Line conduction



### 2. Radiated emission



## Conditions

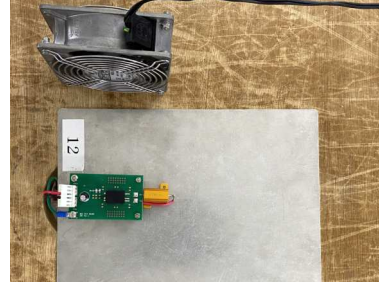
Test : EMI  
Model Name: MUS3□□

## ○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



## ○Testing circuitry

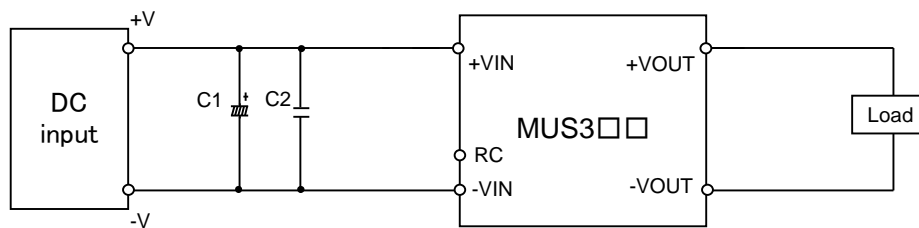


Fig.1 MUS305□, MUS312□, MUS324□ Testing circuitry

C1 :	MUS305□	16V 220 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS312□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS324□	-	
C2 :	MUS305□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS312□	25V 22 $\mu$ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUS324□	50V 10 $\mu$ F	Ceramic capacitor (C3216X7R1H106KT TDK)

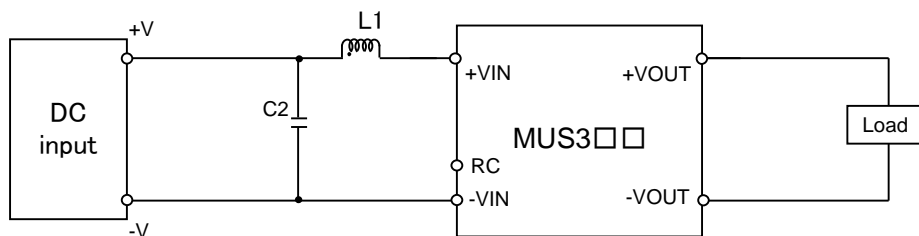


Fig.2 MUS348□ Testing circuitry

C2 :	MUS348□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS348□	520mA 15 $\mu$ H	Inductor(LQH32PN150MN0L MURATA MANUFACTURING)